


<b>Search Notes</b>  	<b>Application/Control No.</b>  10516417	<b>Applicant(s)/Patent Under Reexamination</b>  SASAKI ET AL.
	<b>Examiner</b>  THANH Y TRAN	<b>Art Unit</b>  2892

SEARCHED			
Class	Subclass	Date	Examiner
257	666, 670, 672, 673, 690, 734, 779, 780, 781, 784, 694, 695, E23.042, E23.01, E23.011, E33.066	7/12/08	TYT

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted: Scott Geyer	7/11/08	TYT
East search (see search history printout)	7/12/08	TYT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
257	666, 670, 672, 673, 690, 734, 779, 780, 781, 784, 694, 695, E23.042, E33.066, E23.01, E23.011	7/12/08	TYT
	CLM. Interference search (see search history printout)	7/14/08	TYT